

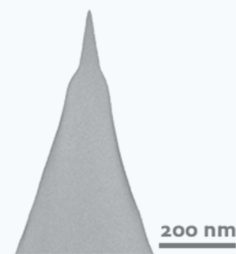
Provided with  
**TrueDimensions**  
Online access to key probe  
parameters for every  
individual tip



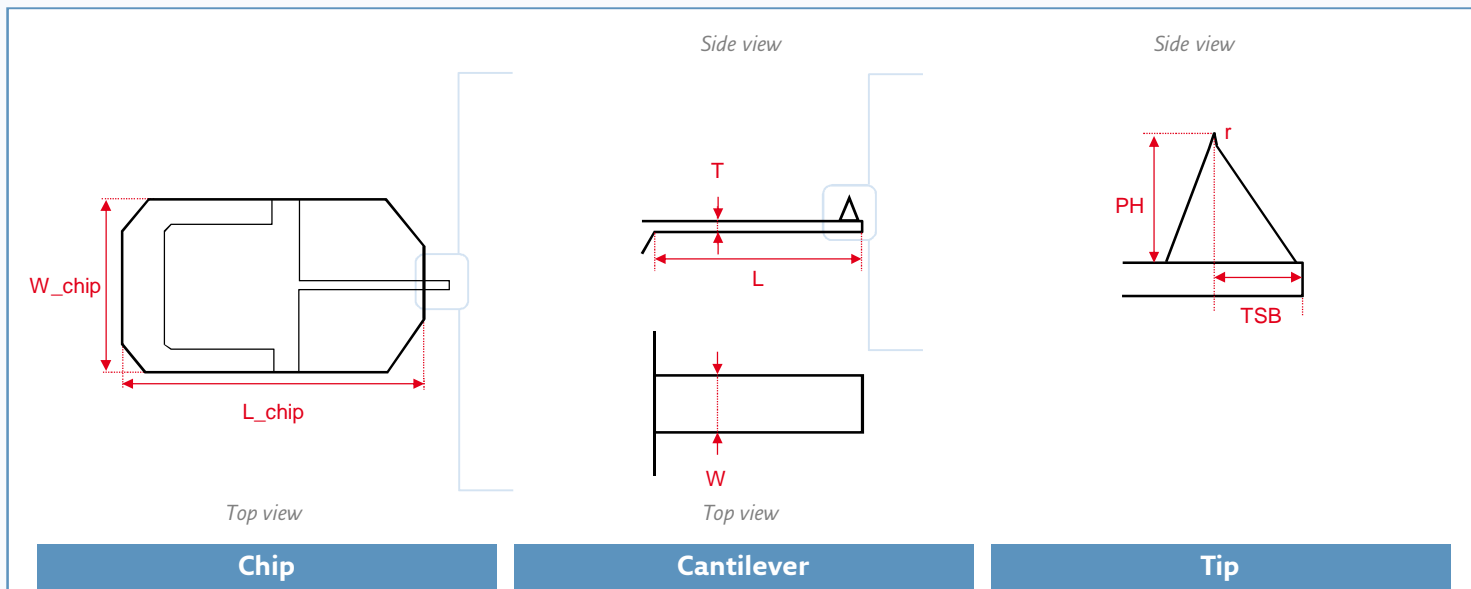
	EBD-RTESP	EBD-RTESPA	EBD-FESPA
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Part number	EBD-RTESP	EBD-RTESPA	EBD-FESPA
<b>Tip</b>			
Sharpness / r	7 nm (<10 nm)	7 nm (<10 nm)	7 nm (<10 nm)
Total tip height / TH	15 µm (10-15 µm)	15 µm (10-15 µm)	15 µm (10-15 µm)
Tip set back / TSB	15 µm (5-25 µm)	15 µm (5-25 µm)	15 µm (5-25 µm)
<b>Cantilever</b>			
Material	Si	Si	Si
Shape	NT-RTESP	NT-RTESPA	NT-FESPA
Length / L	120 µm (±5 µm)	120 µm (±5 µm)	225 µm (±25 µm)
Width / W	30 µm (±2 µm)	30 µm (±2 µm)	28 µm (±5 µm)
Thickness / T	4.4 µm (±0.5 µm)	4.4 µm (±0.5 µm)	3 µm (±0.5 µm)
Force constant* / k	40 N/m (±20 N/m)	40 N/m (±20 N/m)	2.8 N/m (1-5 N/m)
Resonance frequency* / f	320 kHz (±50 kHz)	320 kHz (±50 kHz)	75 kHz (±25 kHz)
Tip side coating	none	none	none
Back side coating	none	reflex	reflex
<b>Chip</b>			
Length / L_chip	3400 µm	3400 µm	3400 µm
Width / W_chip	1500 µm	1500 µm	1500 µm
Thickness / T_chip	315 µm	315 µm	315 µm
Alignment grooves	no	no	yes

- Consistent sharpness
- Diamond-like durability
- Starting at \$50



n/a: specification not applicable for this product | \*Values are calculated from the (measured) cantilever geometry. Actual values of >90% of all probes are guaranteed to be within the specified range.



For more information, visit  
[www.nanotools.com](http://www.nanotools.com)

nanotools GmbH  
Reichenbachstraße 33  
D-80469 Munich  
Phone +49 (0)89 12 11 38-0  
[info@nanotools.com](mailto:info@nanotools.com)



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